

Notice of References Cited	Application/Control No. 10/735,078		Applicant(s)/Patent Under Reexamination WEILLER ET AL.	
	Examiner Kaj K. Olsen		Art Unit 1753	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0217928	11-2003	Lin et al.	205/109
*	B	US-2003/0137083	07-2003	Ko et al.	264/449
*	C	US-5,130,009	07-1992	Marsoner et al.	204/403.11
*	D	US-4,267,506	05-1981	Shiell, Thomas J.	324/761
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Briseno et al, Polymer Preprints 8-2003, 44(2), p. 140.			
	V	Liu et al, Chemistry A European Journal, 2-2003, 9 (3), pp. 604-611			
	W	Pinto et al, Applied Physics Letters, 83(20), 11-2003, pp. 4244-4246.			
	X	Yun et al, Proceedings of SPIE Vol. 5220 Nanofabrication Technologies, 8-2003, pp. 37-45.			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.